N-channel LFPAK 80 V 12.9 m Ω standard level MOSFET

Rev. 01 — 25 June 2009

Product data sheet

1. Product profile

Table 1.

1.1 General description

Standard level N-channel MOSFET in LFPAK package qualified to 175 °C. This product is designed and qualified for use in a wide range of industrial, communications and domestic equipment.

1.2 Features and benefits

- Advanced TrenchMOS provides low RDSon and low gate charge
- High efficiency gains in switching power converters

1.3 Applications

Quick reference

- DC-to-DC converters
- Lithium-ion battery protection
- Load switching

1.4 Quick reference data

- Improved mechanical and thermal characteristics
- LFPAK provides maximum power density in a Power SO8 package
- Motor control
- Server power supplies

Table 1.	QUICK TETETETICE					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 150 °C	-	-	80	V
I _D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u>	-	-	60	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	106	W
Tj	junction temperature		-55	-	175	°C
Avalanc	he ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 55 A; V_{sup} \leq 80 V; R_{GS} = 50 Ω ; unclamped	-	-	70	mJ
Dynamic	characteristics					
Q_{GD}	gate-drain charge	V_{GS} = 10 V; I_D = 25 A; V_{DS} = 40 V; see <u>Figure 14</u> ; see <u>Figure 15</u>	-	8	-	nC
Q _{G(tot)}	total gate charge	V_{GS} = 10 V; I_D = 25 A; V_{DS} = 40 V; see <u>Figure 14</u> ; see <u>Figure 15</u>	-	37	-	nC
Static ch	aracteristics					
R _{DSon}	drain-source on-state	V_{GS} = 10 V; I _D = 15 A; T _j = 100 °C; see <u>Figure 12</u>	-	-	19.8	mΩ
	resistance	V_{GS} = 10 V; I _D = 15 A; T _j = 25 °C; see <u>Figure 13</u>	-	9.7	12.9	mΩ



2. Pinning information

Table 2.	Pinning	information				
Pin	Symbol	Description	Simplified outline	Graphic symbol		
1	S	source		_		
2	S	source	mb			
3	S	source				
4	G	gate	q;			
mb	D	mounting base; connected to drain	$\begin{array}{c} \begin{array}{c} \begin{array}{c} \end{array} \\ \begin{array}{c} \end{array} \\ 1 \end{array} \\ \begin{array}{c} 2 \end{array} \\ \begin{array}{c} 3 \end{array} \\ \begin{array}{c} 4 \end{array} \end{array}$	mbb076 S		
			SOT669 (LFPAK)			

3. Ordering information

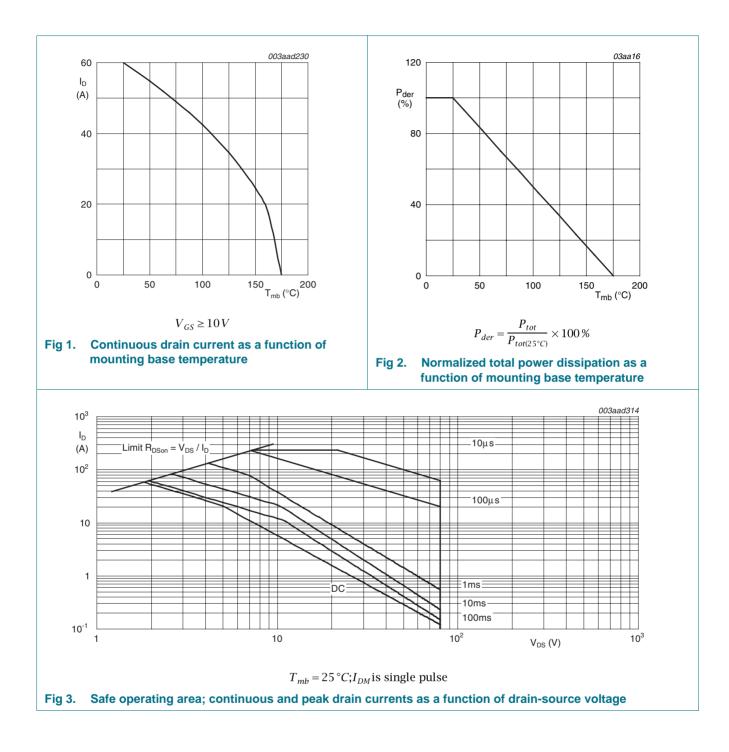
Table 3. Ordering information						
Type number	Package					
	Name	Description	Version			
PSMN013-80YS	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669			

4. Limiting values

Table 4.Limiting values

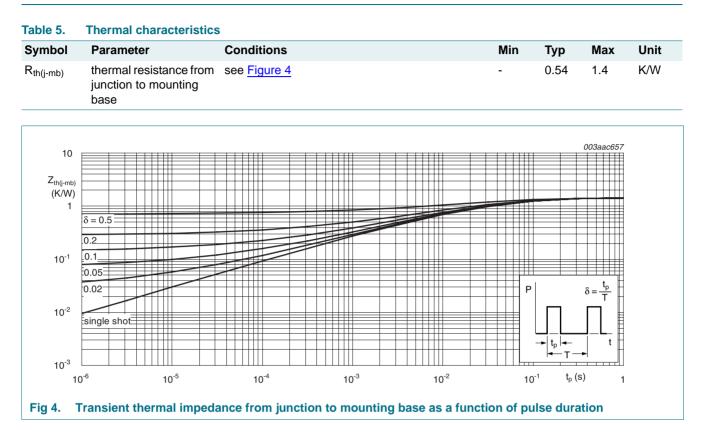
In accordance with the Absolute Maximum Rating System (IEC 60134).

Sumbol	Deremeter	Conditions	Mire	Mox	l lm it
Symbol	Parameter	Conditions	Min	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 150 °C	-	80	V
V _{DGR}	drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$	-	80	V
V _{GS}	gate-source voltage		-20	20	V
I _D	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 100 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{100 \text{ Figure 1}}$	-	42	А
		V_{GS} = 10 V; T_{mb} = 25 °C; see <u>Figure 1</u>	-	60	А
I _{DM}	peak drain current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$; see Figure 3	-	233	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	106	W
T _{stg}	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
T _{sld(M)}	peak soldering temperature		-	260	°C
Source-dr	ain diode				
I _S	source current	T _{mb} = 25 °C	-	60	А
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-	233	А
Avalanche	e ruggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_{D} = 55 A; V_{sup} ≤ 80 V; R_{GS} = 50 $\Omega;$ unclamped	-	70	mJ



N-channel LFPAK 80 V 12.9 mΩ standard level MOSFET

5. Thermal characteristics



N-channel LFPAK 80 V 12.9 mΩ standard level MOSFET

6. Characteristics

Table 6. Characteristics

Tested to JEDEC standards where applicable.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
V _{(BR)DSS} drain-source breakdown voltage		$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = -55 \ ^{\circ}C$	73	-	-	V
		$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^\circ C$	80	-	-	V
V _{GS(th)}	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ °C}; \text{ see}$ Figure 10; see Figure 11	1	-	-	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ °C}; \text{ see}$ Figure 10; see Figure 11	-	-	4.6	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C}; \text{ see}$ Figure 10; see Figure 11	2	3	4	V
I _{DSS}	drain leakage current	V _{DS} = 80 V; V _{GS} = 0 V; T _j = 25 °C	-	-	3	μA
		$V_{DS} = 80 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 125 \text{ °C}$	-	-	40	μA
I _{GSS}	gate leakage current	V_{GS} = -20 V; V_{DS} = 0 V; T_j = 25 °C	-	-	100	nA
		$V_{GS} = 20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nA
R _{DSon}	drain-source on-state resistance	V _{GS} = 10 V; I _D = 15 A; T _j = 175 °C; see <u>Figure 12</u>	-	-	31	mΩ
		V_{GS} = 10 V; I_D = 15 A; T_j = 100 °C; see Figure 12	-	-	19.8	mΩ
		V_{GS} = 10 V; I_D = 15 A; T_j = 25 °C; see Figure 13	-	9.7	12.9	mΩ
R _G	internal gate resistance (AC)	f = 1 MHz	-	0.68	-	Ω
Dynamic o	characteristics					
Q _{G(tot)} total ga	total gate charge	$I_D = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 10 \text{ V}$	-	31	-	nC
		$I_D = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 10 \text{ V}; \text{ see}$ Figure 14; see Figure 15	-	37	-	nC
Q _{GS}	gate-source charge	I_D = 25 A; V_{DS} = 40 V; V_{GS} = 10 V; see	-	11	-	nC
Q _{GS(th)}	pre-threshold gate-source charge	Figure 14; see Figure 15	-	7	-	nC
Q _{GS(th-pl)}	post-threshold gate-source charge		-	4	-	nC
Q _{GD}	gate-drain charge		-	8	-	nC
V _{GS(pl)}	gate-source plateau voltage	$I_D = 25 \text{ A}; V_{DS} = 40 \text{ V}$	-	4.8	-	V
C _{iss}	input capacitance	$V_{DS} = 40 \text{ V}; \text{ V}_{GS} = 0 \text{ V}; \text{ f} = 1 \text{ MHz};$	-	2420	-	рF
C _{oss}	output capacitance	T _j = 25 °C; see Figure 16	-	224	-	pF
C _{rss}	reverse transfer capacitance		-	125	-	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 40 \text{ V}; \text{ R}_{L} = 1.6 \Omega; \text{ V}_{GS} = 10 \text{ V};$	-	20	-	ns
t _r	rise time	$R_{G(ext)} = 4.7 \Omega$	-	15	-	ns
t _{d(off)}	turn-off delay time		-	37	-	ns
t _f	fall time		-	10	-	ns

Symbol

Source-drain diode

PSMN013-80YS

Мах

Unit

N-channel LFPAK 80 V 12.9 mΩ standard level MOSFET

Min

Тур

V _{SD}	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j$ Figure 17	= 25 °C; see	-	0.84	1.2	V
t _{rr}	reverse recovery time	$I_{\rm S} = 50 \text{ A}; \text{ d}I_{\rm S}/\text{d}t = 100 \text{ A}$	√μs; V _{GS} = 0 V;	-	52	-	ns
Qr	recovered charge	$V_{DS} = 40 V$		-	91	-	nC
(A	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	003aad181	4000 C (pF) 3000			003aad187	
	30		2000			C _{rss}	
	10	4.5	1000				
	0 0.5 1	$V_{GS}(V) = 4$ 1.5 $V_{DS}(V)$ 2	0 <mark>0 0</mark>	3 6	9	12 V _{GS} (V)	
Fig 5.	Output characteristics: of function of drain-source		45 R _{DSon}	nd reverse trai			
Į	50		(mΩ) 35				
4	40						
;	20 T _j = 150 °C		25				
:	30 T _j = 150 °C	T _j = 25 °C		5 10	15		
:	$ \begin{array}{c} 30 \\ \hline T_{j} = 150 \circ C \\ \hline 10 \\ \hline 0 \end{array} $	$T_{j} = 25 \text{ °C}$ $4 \text{ V}_{GS} (V) \text{ 6}$	15	5 10 $T_i = 25 ^{\circ}C;I$			

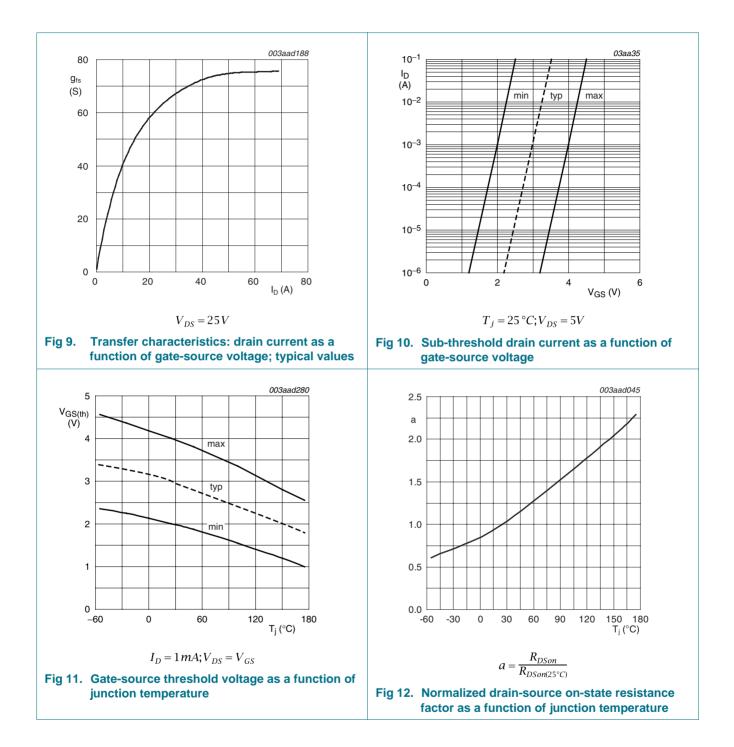
Table 6. Characteristics ...continued

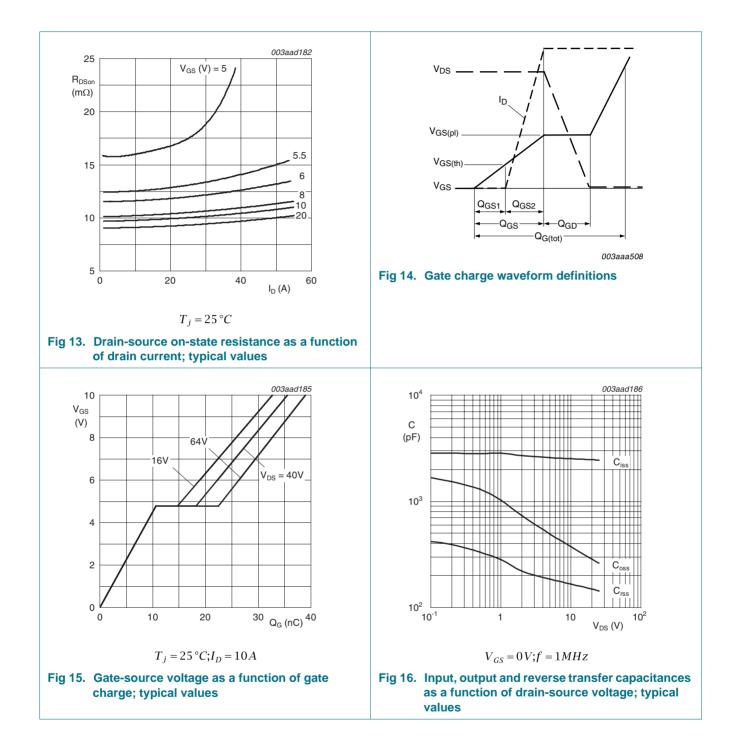
Parameter

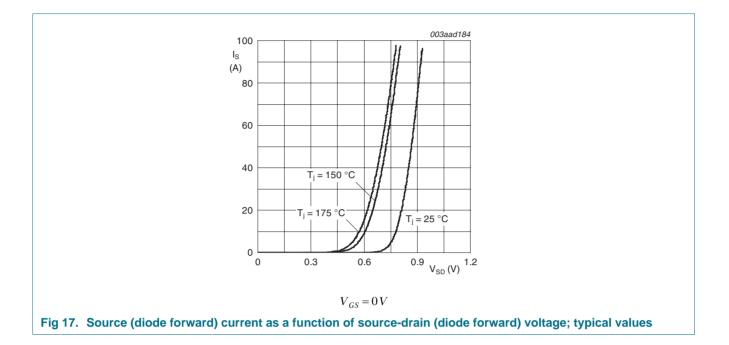
Tested to JEDEC standards where applicable.

Conditions

© NXP B.V. 2009. All rights reserved.







N-channel LFPAK 80 V 12.9 mΩ standard level MOSFET

7. Package outline

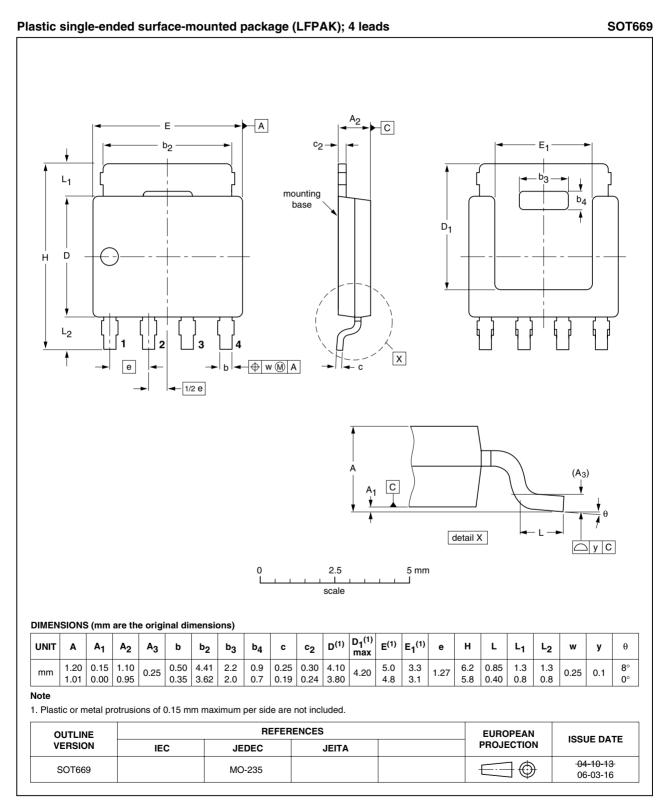


Fig 18. Package outline SOT669 (LFPAK)

PSMN013-80YS_1

N-channel LFPAK 80 V 12.9 mΩ standard level MOSFET

8. Revision history

Table 7. Revision his	able 7. Revision history			
Document ID	Release date	Data sheet status	Change notice	Supersedes
PSMN013-80YS_1	20090625	Product data sheet	-	-

9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions"

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

9.2 Definitions

Draft — The document is a draft version only. The content is still under internal review and subject to formal approval, which may result in modifications or additions. NXP Semiconductors does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

Short data sheet — A short data sheet is an extract from a full data sheet with the same product type number(s) and title. A short data sheet is intended for quick reference only and should not be relied upon to contain detailed and full information. For detailed and full information see the relevant full data sheet, which is available on request via the local NXP Semiconductors sales office. In case of any inconsistency or conflict with the short data sheet, the full data sheet shall prevail.

9.3 Disclaimers

General — Information in this document is believed to be accurate and reliable. However, NXP Semiconductors does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information.

Right to make changes — NXP Semiconductors reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

Suitability for use — NXP Semiconductors products are not designed, authorized or warranted to be suitable for use in medical, military, aircraft, space or life support equipment, nor in applications where failure or malfunction of an NXP Semiconductors product can reasonably be expected to result in personal injury, death or severe property or environmental damage. NXP Semiconductors accepts no liability for inclusion and/or use of NXP Semiconductors products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk.

Applications — Applications that are described herein for any of these products are for illustrative purposes only. NXP Semiconductors makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Quick reference data — The Quick reference data is an extract of the product data given in the Limiting values and Characteristics sections of this document, and as such is not complete, exhaustive or legally binding.

Limiting values — Stress above one or more limiting values (as defined in the Absolute Maximum Ratings System of IEC 60134) may cause permanent damage to the device. Limiting values are stress ratings only and operation of the device at these or any other conditions above those given in the Characteristics sections of this document is not implied. Exposure to limiting values for extended periods may affect device reliability.

Terms and conditions of sale — NXP Semiconductors products are sold subject to the general terms and conditions of commercial sale, as published at http://www.nxp.com/profile/terms, including those pertaining to warranty, intellectual property rights infringement and limitation of liability, unless explicitly otherwise agreed to in writing by NXP Semiconductors. In case of any inconsistency or conflict between information in this document and such terms and conditions, the latter will prevail.

No offer to sell or license — Nothing in this document may be interpreted or construed as an offer to sell products that is open for acceptance or the grant, conveyance or implication of any license under any copyrights, patents or other industrial or intellectual property rights.

Export control — This document as well as the item(s) described herein may be subject to export control regulations. Export might require a prior authorization from national authorities.

9.4 Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

TrenchMOS — is a trademark of NXP B.V.

10. Contact information

For more information, please visit: http://www.nxp.com

For sales office addresses, please send an email to: salesaddresses@nxp.com

PSMN013-80YS_1

N-channel LFPAK 80 V 12.9 mΩ standard level MOSFET

11. Contents

1	Product profile1
1.1	General description1
1.2	Features and benefits1
1.3	Applications1
1.4	Quick reference data1
2	Pinning information2
3	Ordering information2
4	Limiting values2
5	Thermal characteristics4
6	Characteristics5
7	Package outline10
8	Revision history11
9	Legal information12
9.1	Data sheet status12
9.2	Definitions12
9.3	Disclaimers
9.4	Trademarks12
10	Contact information12

Please be aware that important notices concerning this document and the product(s) described herein, have been included in section 'Legal information'.

© NXP B.V. 2009.



For more information, please visit: http://www.nxp.com For sales office addresses, please send an email to: salesaddresses@nxp.com

Date of release: 25 June 2009 Document identifier: PSMN013-80YS_1

All rights reserved.